

BSP127-VB Datasheet

N-Channel 250 V (D-S) MOSFET

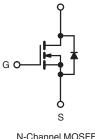
PRODUCT SUMMA	RY	
V _{DS} (V)	250)
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.0
Q _g (Max.) (nC)	8.2	
Q _{gs} (nC)	1.8	
Q _{gd} (nC)	4.5	
Configuration	Sing	le

FEATURES

- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	less otherwis	se noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	250	v	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D	0.79	
Continuous Drain Current		$T_C = 100 \ ^\circ C$		0.50	А
Pulsed Drain Current ^a		I _{DM}	6.3		
Linear Derating Factor		0.025	0.025		
Linear Derating Factor (PCB Mount) ^e			0.017		
Single Pulse Avalanche Energy ^b			E _{AS}	50	mJ
Repetitive Avalanche Current ^a		I _{AR}	0.79	A	
Repetitive Avalanche Energy ^a		E _{AR}	0.31	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$		D	3.1	w	
laximum Power Dissipation (PCB Mount) $^{\circ}$ T _A = 25 $^{\circ}$ C		PD	2.0		
Peak Diode Recovery dV/dt ^c		dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	- °C	
Soldering Recommendations (Peak Temperature) ^d	for	10 s	-	300	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 128 mH, $R_g = 25 \Omega$, $I_{AS} = 0.79 \text{ A}$ (see fig. 12). c. $I_{SD} \le 2.7 \text{ A}$, dl/dt $\le 65 \text{ A}/\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 150 \text{ °C}$.

d. 1.6 mm from case.

e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RAT	INGS				
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	60	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	40	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.39	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	: V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	-	: 250 V, V _{GS} = 0 V 7, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.47 A ^b	_	2.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 0.47 A	0.50	-	-	S
Dynamic		•					
Input Capacitance	C _{iss}		V _{GS} = 0 V, V _{DS} = 25 V,		140	-	pF
Output Capacitance	C _{oss}				42	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.	0 MHz, see fig. 5	-	9.6	-	
Total Gate Charge	Qg		I_{D} = 2.7 A, V_{DS} = 200 V, see fig. 6 and 13 $^{\rm b}$	-	-	8.2	nC
Gate-Source Charge	Q _{qs}	V _{GS} = 10 V		-	-	1.8	
Gate-Drain Charge	Q _{qd}			-	-	4.5	
Turn-On Delay Time	t _{d(on)}			-	7.0	-	
Rise Time	t _r	V_{DD} = 125 V, I_D = 2.7 A, R_g = 24 Ω,R_D = 45 $\Omega,$ see fig. 10 $^{\rm b}$		-	7.6	-	ns
Turn-Off Delay Time	t _{d(off)}			-	16	-	
Fall Time	t _f			-	7.0	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	nH
Internal Source Inductance	L _S			-	6.0	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol		-	0.79	
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	6.3	A
Body Diode Voltage	V _{SD}	T _J = 25 °C,	$I_{\rm S}$ = 0.79 A, $V_{\rm GS}$ = 0 V ^b	-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 2.7 \text{ A}, dI/dt = 100 \text{ A/}\mu\text{s}^{\text{b}}$		-	190	390	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.64	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is dor	ninated b	$v L_{s}$ and	L _D)

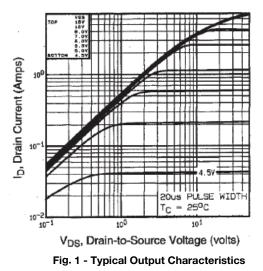
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300~\mu s;~duty~cycle \leq 2~\%.$



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



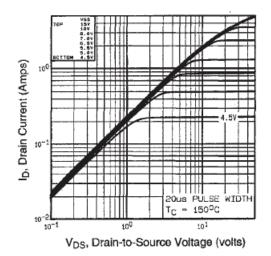


Fig. 2 - Typical Output Characteristics

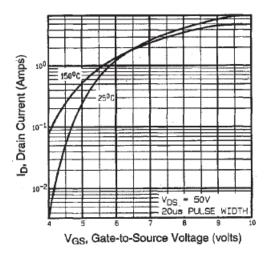


Fig. 3 - Typical Transfer Characteristics

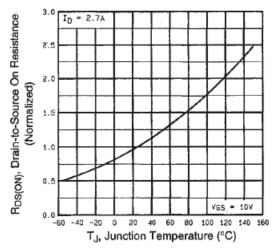


Fig. 4 - Normalized On-Resistance vs. Temperature

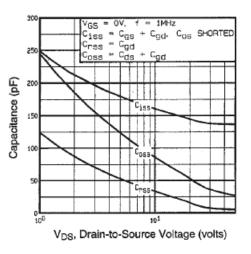


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

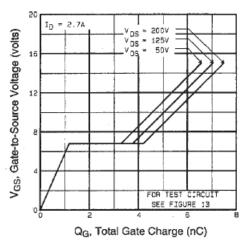


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



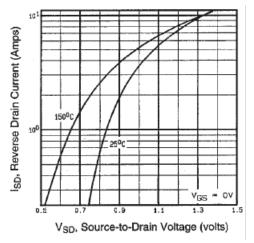


Fig. 7 - Typical Source-Drain Diode Forward Voltage

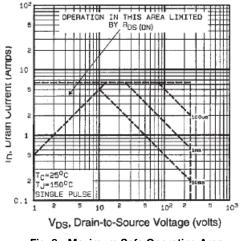


Fig. 8 - Maximum Safe Operating Area

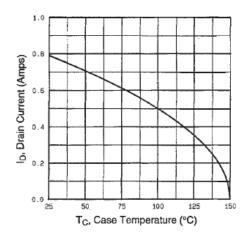


Fig. 9 - Maximum Drain Current vs. Case Temperature

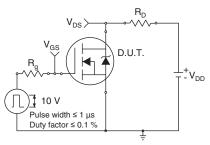


Fig. 10a - Switching Time Test Circuit

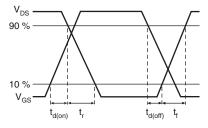


Fig. 10b - Switching Time Waveforms

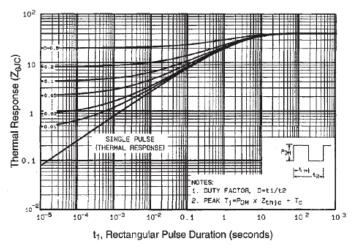


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



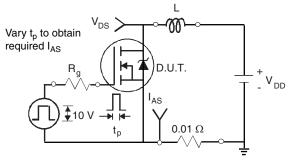


Fig. 12a - Unclamped Inductive Test Circuit

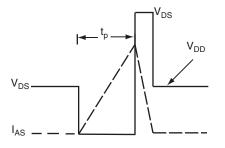


Fig. 12b - Unclamped Inductive Waveforms

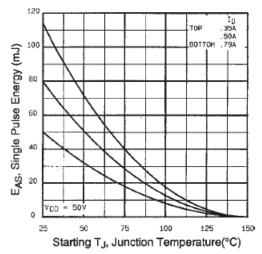


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

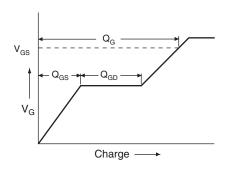


Fig. 13a - Basic Gate Charge Waveform

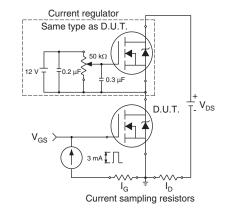
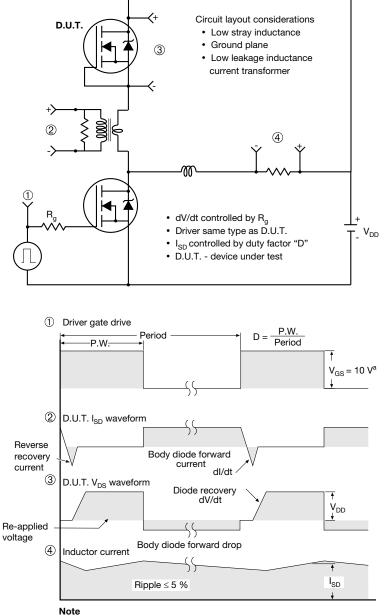


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

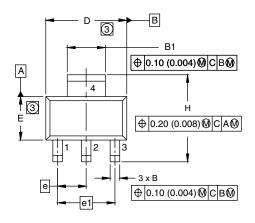


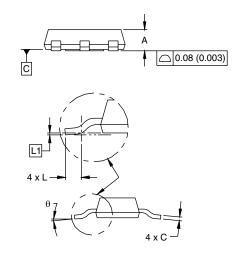
a. V_{GS} = 5 V for logic level devices

Fig.14 - For N-Channel



SOT-223 (HIGH VOLTAGE)





	MILLI	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181 BSC		
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	-	
L1	0.061 BSC		0.002	4 BSC	
θ	-	10'	-	10'	

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimensions are shown in millimeters (inches).

3. Dimension do not include mold flash.

4. Outline conforms to JEDEC outline TO-261AA.



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